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Ecloud Build-Up Simulations for the FNAL MI for a Mixed Fill Pattern: Dependence on Peak SEY and Pulse Intensity During the Ramp

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Abstract

We present simulation results of the build-up of the electron-cloud density \( n_e \) in three regions of the FNAL Main Injector (MI) for a beam fill pattern made up of 5 double booster batches followed by a 6th single batch. We vary the pulse intensity in the range \( N_t = (2 - 5) \times 10^{13} \), and the beam kinetic energy in the range \( E_k = 8 - 120 \) GeV. We assume a secondary electron emission model qualitatively corresponding to Tin, except that we let the peak value of the secondary electron yield (SEY) \( \delta_{\text{max}} \) vary as a free parameter in a fairly broad range.

Our main conclusions are: (1) At fixed \( N_t \) there is a clear threshold behavior of \( n_e \) as a function of \( \delta_{\text{max}} \) in the range \( 1.1 - 1.3 \). (2) At fixed \( \delta_{\text{max}} \), there is a threshold behavior of \( n_e \) as a function of \( N_t \) provided \( \delta_{\text{max}} \) is sufficiently high; the threshold value of \( N_t \) is a function of the characteristics of the region being simulated. (3) The dependence on \( E_k \) is weak except possibly at transition energy.

Most of these results were informally presented to the relevant MI personnel in April 2010.

INTRODUCTION

The desire to assess the impact of the electron-cloud effect on the MI upgrade [1] has motivated the measurement of the incident electron flux \( J_e \), on the walls of the MI vacuum chamber by means of a RFA electron detector installed in a field-free region [2] for various high-intensity beam fill patterns [3], and of the measurement of the semi-local average of the volumetric electron-cloud density \( n_e \) by means of the microwave dispersion technique [4, 5].

In this note we present simulation results for \( n_e \) in three different regions of the chamber, which we label “edet”, “bend”, and “FFellip”. The first one, “edet,” represents a round-pipe field-free region where the RFA is installed. The other two represent regions where the microwave transmission measurements have been performed: “bend” represents a dipole bending magnet, and “FFellip” a field-free region, both having elliptical chamber cross section. Table 1 provides the assumed values for the relevant parameters.

In the exercises considered here vary \( E_k \), bunch intensity \( N_b \), and \( \delta_{\text{max}} \) in the range specified in Table 2, but not in all possible combinations (here \( N_b \) is the bunch intensity in any of the first 5 batches; the bunch intensity in the 6th batch is always 50% of that in the first five). Detailed parameter values for each case are explained below. Preliminary results were presented at the PAC09 [6].

The results were obtained with the 2D program POSINST, which simulates the electron-cloud build-up and decay in a specific region of the chamber under the action of a prescribed beam fill pattern [7–10]. All results here are based on the simulation for only one full machine revolution; this is sufficiently long for the electron cloud to reach steady state, which typically occurs within the first \( \sim 2 \mu s \) following beam injection into an empty chamber.

ASSUMPTIONS

We assume a beam fill pattern similar to what has been used in the corresponding measurements, consisting of 6 batches in which the first 5 are obtained by slip-stacking booster batches; the 6th batch bunch intensity is 50% of that in any of the first five. Owing to an initial misunderstanding, we used two slightly different patterns for different sets of simulation runs (see Fig. 2). The difference in the results for these two is expected to be negligible; for the sake of the record, however, we specify in the results below which parameter was used in which case.

Although the beta functions and the transverse RMS beam sizes are different in the three sections, we set them equal for the purpose of the exercises carried out in this note. The bunch sizes quoted in Table 1 for \( E_k = 8 \) GeV correspond to a normalized 95% emittance \( \epsilon_{\text{95}} = 15 \times 10^{-6} \) m–rad. For higher \( E_k \), we simply scale these \( \epsilon \)'s in proportion to \( \gamma^{-1/2} \), where \( \gamma \) is the usual relativistic factor for the beam.

In actuality, the longitudinal bunch shape, at least in the first 5 batches, is fairly flat as a result of the stacking process; however, to simplify things, we have assumed that the shape is Gaussian with an RMS bunch length (in time) \( \sigma_t = \tau_{\text{95}}/4 \), where \( \tau_{\text{95}} \) is the 95% bunch duration plotted in Fig. 1. Simulations comparing Gaussian vs. flat longitudinal bunch profiles for the LHC [11], as well as for the MI (unpublished), showed very small differences in similar parameter regimes. Finally, we have assumed that the three RMS bunch sizes are the same for all bunches in the ring.

The electron-cloud build-up is seeded by ionization of residual gas. The ionization electron creation rate (electrons generated per proton per unit length of beam traversal) quoted in Tab. 2 is computed from the formula

\[
n' [m^{-1}] = 3.284 \sigma_t \text{ [Mbarn]} \times P \text{ [Torr]} \times \frac{294}{T \text{ [K]}}
\]
However, in essentially all cases, it is the secondary electron emission that dominates the intensity of the process. The model used here for the secondary electron emission spectrum corresponds, approximately, to that of TiN. However, we take $\delta_{\text{max}}$ as a free parameter that we exercise in a fairly broad range. Ideally, by fitting the results obtained here to measurements, one might determine $\delta_{\text{max}}$. The validity of this fit assumes, of course, that all other relevant parameters are frozen at some realistic value. While previous work indicates that the values of these other parameters are reasonably realistic, we have not checked the above assumption.

Essentially all the present results were informally presented to the relevant RF personnel in April 2010. This work amounts to a logical continuation of the studies initiated in early 2006 [12]. A complete publication list can be found in Ref. 13.

**RESULTS**

*Build-up at fixed $E_k$*

There is evidence that the electron cloud signal in the RPA has a significant dependence on $E_k$, peaking at $E_k \approx 60$ GeV. On the other hand, it appears that the microwave dispersion measurements show a signal that is fairly independent of $E_k$ except near transition at $E_k \approx 20$ GeV [14]. Furthermore, the dispersion measurements have been studied in a bit more detail at 120 GeV, hence our choices $E_k = 60$ GeV for “edet,” and $E_k = 120$ GeV for “bend” and “FFellip.”

Results for $n_c$ as a function of time during one revolution period are shown in Figs. 4, 5, 6 for the 3 regions considered. Each of the 4 plots in each case corresponds to 4 different values of $N_r$, as indicated. The simulations for all three regions show a clear threshold of $n_c$ as a function

![Figure 1: Measured 95% bunch duration during the ramp as a function of the beam momentum.](image)

![Figure 2: Fill patterns used in the simulations for one machine revolution, for the case $N_r = 1 \times 10^{11}$. The bottom numbers (1e11,...) represent the bunch population. The top numbers (82,44,...) represent the number of filled or empty buckets. Pattern “hi_int.mixed” has 451 bunches, “hi_int.mixed_rev” 492.](image)

![Figure 3: Bunch intensity in any of the first 5 trains as a function of total beam intensity for the two fill patterns considered, shown in Fig. 2. The bunch intensity in the 6th train is always 50% of the value in any of the first 5 trains.](image)
Table 1: Assumed local parameters in the three simulated regions.

<table>
<thead>
<tr>
<th>quantity</th>
<th>symbol [unit]</th>
<th>“edet”</th>
<th>“bend”</th>
<th>“FFellip”</th>
</tr>
</thead>
<tbody>
<tr>
<td>Beta functions</td>
<td>( (\beta_x, \beta_y) ) [m]</td>
<td>(20, 30)</td>
<td>(20, 30)</td>
<td>(20, 30)</td>
</tr>
<tr>
<td>RMS transv. beam sizes at ( E_b = 8 ) GeV</td>
<td>( (\sigma_x, \sigma_y) ) [mm]</td>
<td>(2.291, 2.806)</td>
<td>(2.291, 2.806)</td>
<td>(2.291, 2.806)</td>
</tr>
<tr>
<td>Pipe cross section</td>
<td>( \cdots ) [\text{\cdot\cdot\cdot}]</td>
<td>round</td>
<td>elliptical</td>
<td>elliptical</td>
</tr>
<tr>
<td>Pipe semiaxes</td>
<td>( (a, b) ) [cm]</td>
<td>(7.3, 7.3)</td>
<td>(6.15, 2.45)</td>
<td>(6.15, 2.45)</td>
</tr>
<tr>
<td>Dipole field at ( E_b = 8 ) GeV</td>
<td>( B ) [T]</td>
<td>0</td>
<td>0.1022</td>
<td>0</td>
</tr>
</tbody>
</table>

Table 2: Assumed global parameters.

<table>
<thead>
<tr>
<th>Ring and beam</th>
<th></th>
</tr>
</thead>
<tbody>
<tr>
<td>Revolution period</td>
<td>( T_0 = 11.07 \mu s )</td>
</tr>
<tr>
<td>RF frequency</td>
<td>( f_{RF} = 53.10 ) MHz</td>
</tr>
<tr>
<td>Harmonic number</td>
<td>( h = 588 )</td>
</tr>
<tr>
<td>Beam kinetic energy</td>
<td>( E_b = 8 ) - 120 GeV</td>
</tr>
<tr>
<td>Bunch profile</td>
<td>3D gaussian</td>
</tr>
<tr>
<td>95% bunch duration</td>
<td>see Figs. 1</td>
</tr>
<tr>
<td>Pulse intensity</td>
<td>( N_t = (2 - 5) \times 10^{13} )</td>
</tr>
<tr>
<td>Bunch intensity</td>
<td>( N_b \simeq (0.4 - 1.1) \times 10^{11} )</td>
</tr>
<tr>
<td>Fill pattern</td>
<td>see Figs. 2 &amp; 3</td>
</tr>
<tr>
<td>Primary e(^{-}) sources</td>
<td></td>
</tr>
<tr>
<td>Residual gas pressure</td>
<td>( P = 20 ) nTorr</td>
</tr>
<tr>
<td>Temperature</td>
<td>( T = 305 ) K</td>
</tr>
<tr>
<td>Ionization cross-section</td>
<td>( \sigma_i = 2 ) Mbarons</td>
</tr>
<tr>
<td>Ionization e(^{-}) creation rate</td>
<td>( 1.266 \times 10^{-7} ) (e/p)/m</td>
</tr>
<tr>
<td>Secondary e(^{-}) parameters</td>
<td></td>
</tr>
<tr>
<td>Range of peak SEY</td>
<td>( \delta_{\text{max}} = 0 - 1.7 )</td>
</tr>
<tr>
<td>Energy at ( \delta_{\text{max}} )</td>
<td>( E_{\text{max}} \simeq 292.6 ) eV</td>
</tr>
<tr>
<td>SEY at 0 energy</td>
<td>( \delta(0) = 0.2374 \times \delta_{\text{max}} )</td>
</tr>
</tbody>
</table>

Simulation parameters

| Primary macromolecules/bunch | 1000 |
| Full no. of macromolecules  | 20000 |
| Full bunch length           | \( L_b = 5 \sigma_s \) |
| Integration time step       | \( (1 \text{ or } 2.5) \times 10^{-11} \) s |
| Space-charge grid           | \( 64 \times 64 \) |

of \( \delta_{\text{max}} \), and also that this threshold value depends clearly on \( N_t \). This threshold dependence had already been noted earlier [15]. For \( N_t > 4 \times 10^{13} \), the threshold in \( \delta_{\text{max}} \) is in the range 1.1-1.3. The region “edet” shows a weaker dependence on \( \delta_{\text{max}} \) than the other two, probably because its larger radius leads to lower electron-wall impact energies, hence to a lower effective SEY. However, when both \( \delta_{\text{max}} \) and \( N_t \) are above threshold, the steady-state value of \( n_e \lesssim 1 \times 10^{12} \) m\(^{-3}\) is similar in all cases, corresponding to \( \lesssim 100\% \) beam neutralization. In these simulations we chose an integration time step \( \Delta t = 1 \times 10^{-11} \) s which, based on prior experience, is sufficiently short to yield numerically stable results. The one-turn averaged \( n_e \) corresponding to the above build-up simulations are shown in Fig. 7 for the 3 regions considered, showing more clearly the threshold behavior as a function of \( N_t \) for each value of \( \delta_{\text{max}} \).

The “bend” exhibits a non-monotonic behavior of \( n_e(N_t) \) for \( \delta_{\text{max}} = 1.3 \). This behavior has also been noticed in simulations for the proposed PS2 and for the SPS [16-18], although not yet experimentally verified. The non-monotonicity can likely be explained by the fact that, as \( N_t \) grows, the average electron-wall impact energy crosses \( E_{\text{max}} \simeq 293 \) eV (where the SEY is maximum) when \( N_t \simeq 3 \times 10^{13} \). This explanation makes sense only when the effective SEY is \( < 1 \) (1) for \( N_t < 3 \times 10^{13} (\geq 3 \times 10^{13}) \), which is valid only for the trace corresponding to \( \delta_{\text{max}} = 1.3 \) in Fig. 7. A full explanation remains to be spelled out in detail, although a qualitative picture can already be based on the average electron-wall impact energy. Experimental tests at the SPS will be conducted in the near future [19].

Build-up during the ramp

In this set of simulations we obtained the average \( n_e \) during the energy ramp, but only for one value of \( N_t \), namely \( 1 \times 10^{11} \), corresponding to \( N_t = 4.305 \times 10^{13} \) for the pattern “hi.int.mixed.” In this case, the integration time step was \( \Delta t = 2.5 \times 10^{-11} \) s, which is adequate. We also used a finer scan in \( \delta_{\text{max}} \) than in the above simulations.

Results are shown in Fig. 8. In general, one observes a weak dependence on \( E_b \) except possibly near transition, which can be explained by the short bunch length. This weak energy dependence is consistent with the microwave dispersion measurements but not with the RFA measurements, a discrepancy that remains to be fully explained. In all cases analyzed we observe again the threshold behavior of \( n_e \) as a function of \( \delta_{\text{max}} \), with a transition in \( \delta_{\text{max}} \simeq 1.1 - 1.3 \).

DISCUSSION

We have examined the electron cloud in the MI for a fill pattern made up of 6 trains, in which the bunch intensity in the 6th train is half of that in the previous 5. This pattern can be achieved in practice by slip-stacking booster...
batches. We have examined pulse intensities in the range \( N_p = (2 - 5) \times 10^{13} \), corresponding to bunch intensities (in the first 5 batches) in the range \( N_b \approx (0.4 - 1.1) \times 10^{11} \). The main conclusions from the results presented here are:

1. At fixed \( N_b \), there is a clear threshold behavior of \( n_e \) as a function of \( \delta_{\text{max}} \) in the region \( \delta_{\text{max}} = 1.1 - 1.3 \). This result is fully consistent with previous simulations we have carried out for the MI.

2. At fixed \( \delta_{\text{max}} \), there is also a threshold behavior of \( n_e \) as a function of \( N_p \), provided \( \delta_{\text{max}} \) is high enough (typically \( \geq 1.3 \)). The threshold value of \( N_p \) depends on the details of the region being simulated: for "bend," \( N_p \approx 2 \times 10^{13} \); for "edt" and "FPellip," \( N_p = (3 - 4) \times 10^{13} \). This result is qualitatively consistent with prior simulations.

3. The electron-cloud average density shows a weak dependence on beam energy except at transition. This qualitative feature is more consistent with the microwave dispersion measurements than with the RFA measurements.

4. When \( \delta_{\text{max}} \) is at or above the transition region, the simulations show deep fluctuations resulting from a "virtual cathode" effect. The fluctuations are partly physical and partly due to numerical artifacts, but do not significantly affect the one-turn averages of \( n_e \). An improved simulation model is called for in order to better understand and control these effects.

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REFERENCES


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Figure 4: Build-up of the average e-cloud density during one turn in a "edet" region, at $E_k = 60$ GeV, for the fill pattern "hi_int_mixed_rev" for $N_t = (2, 3, 4, 5) \times 10^{13}$, as labeled. Each trace corresponds to the indicated value of the peak SEY $\delta_{\text{max}}$. 
Figure 5: Build-up of the average ecloud density during one turn in a "bend" region, at $E_k = 120$ GeV, for the fill pattern "hi_int.mixed.rev" for $N_t = (2, 3, 4, 5) \times 10^{13}$, as labeled. Each trace corresponds to the indicated value of the peak SEY $\delta_{\text{max}}$.

Figure 6: Build-up of the average ecloud density during one turn in a "FFellip" region, at $E_k = 120$ GeV, for the fill pattern "hi_int.mixed.rev" for $N_t = (2, 3, 4, 5) \times 10^{13}$, as labeled. Each trace corresponds to the indicated value of the peak SEY $\delta_{\text{max}}$. 
Figure 7: Average ecloud density at a given beam energy, as indicated, as a function of pulse intensity \(N_t\) for the pattern "hi_int.mixed.rev." Each trace corresponds to the indicated value of the peak SEY \(\delta_{max}\).

Figure 8: One-turn average of \(n_e\) during the ramp in each of the 3 regions simulated, for the fill pattern "hi_int.mixed" for \(N_b = 1 \times 10^{13}\) \((N_t = 4.305 \times 10^{13})\). Each trace corresponds to the indicated value of the peak SEY \(\delta_{max}\). The abscissa is the full beam energy, \(E_b + m_pc^2\).